

Electronics

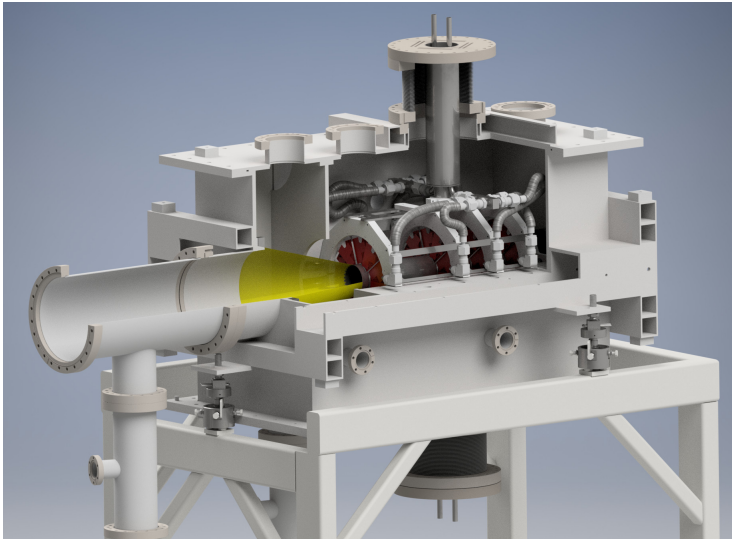
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on behalf of the PANDA Luminosity Detector Group

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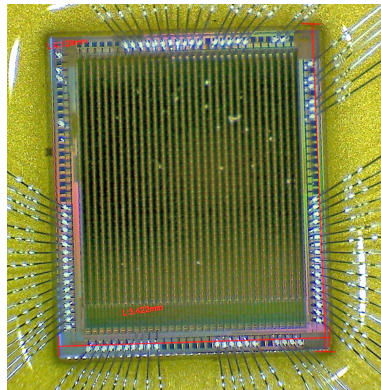
Luminosity Detector Overview



- High Voltage Monolithic Active Pixel Sensor
- Under development (Mu3e group in Heidelberg)
- Standard CMOS production
- Digital part on chip
- High bias voltage increases S/N
- Pixel size: $80\ \mu\text{m} \times 80\ \mu\text{m}$
- Thickness: $\sim 50\ \mu\text{m}$

- Dimensions: $\sim 2 \times 2.3\ \text{cm}^2$
Prototype: $1.08 \times 1.95\ \text{cm}^2$
- Expected power consumption $< 300\ \text{mW}/\text{cm}^2$

MuPix prototype $3 \times 4\ \text{mm}^2$



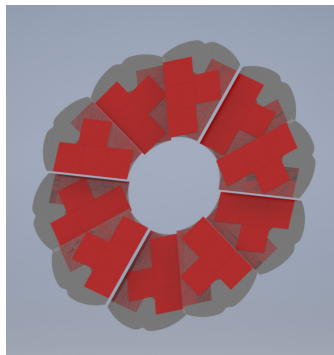
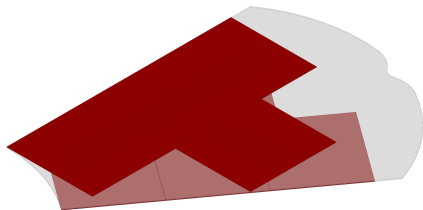
Arrangement of HV-MAPS

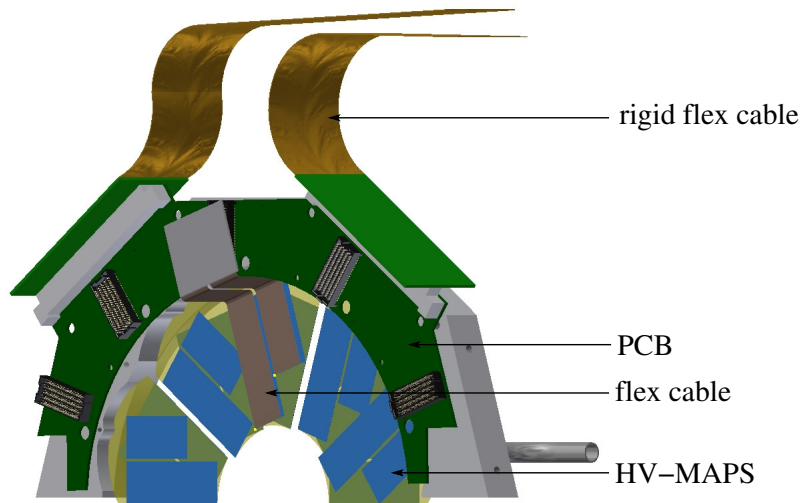
320 sensors ($50\ \mu\text{m}$ thick) glued on 40 CVD diamond wafers

- 4 planes with 10 modules
- Full azimuthal range

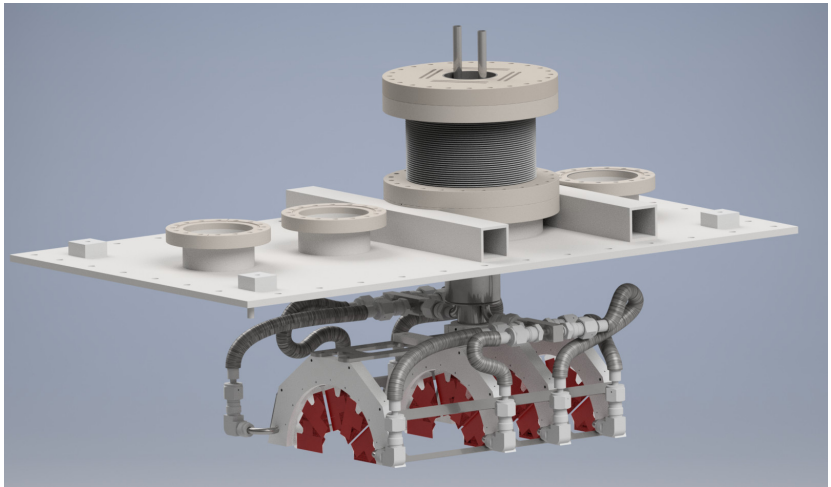
Advantages of CVD diamond:

- very high thermal conductivity
- very hard material
⇒ very thin supply structure ($200\ \mu\text{m}$)

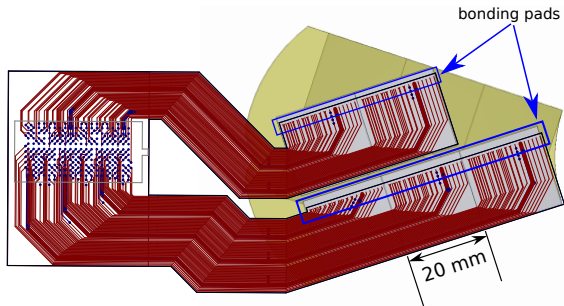




Signal Routing

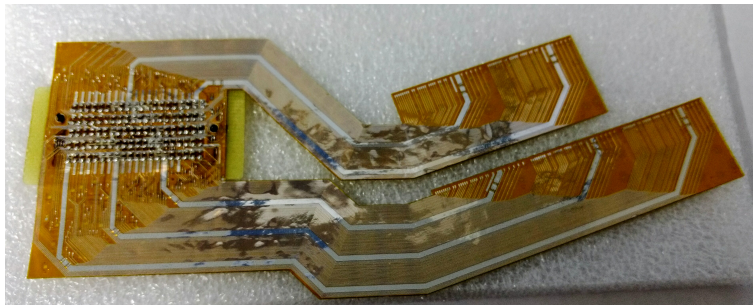


Connection of HV-MAPS



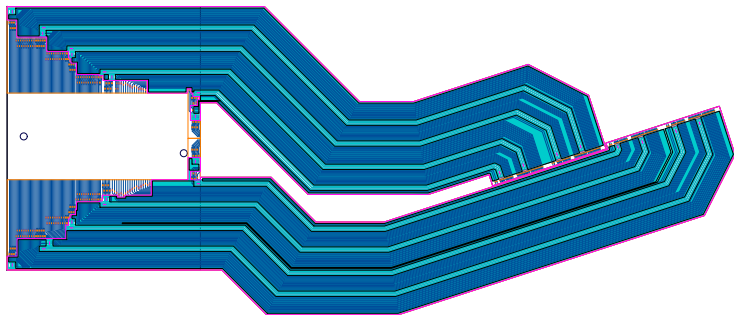
- Characteristics:
 - Trace material: aluminum
 - Trace width: $> 100 \mu\text{m}$
 - Trace thickness: $14 \mu\text{m}$
 - Cable thickness: $\approx 60 \mu\text{m}$
 - Pads for wire bonding
- Advantage of aluminum: Short radiation length
→ Average $X/X_0 = 0.32 \%$
- Disadvantage of aluminum: High electrical resistance
→ voltage drop
→ high power dissipation

Connection of HV-MAPS



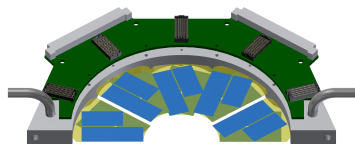
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Flex Cable for Prototype Sensor



Changes:

- Trace width: $> 80 \mu\text{m}$
- Cable thickness: $\approx 100 \mu\text{m}$
- Pads for TAB bonding
- Switch of bottom and top layer
- Cable consist of 3 parts



- PCB on both sides of the half plane
- Power dissipating components attached to the surface
- Radiation tests with electronic parts were made at COSY

Expected radiation dose: < 0.1 kGy

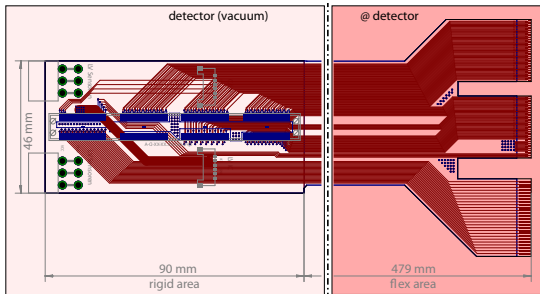
5 kGy, 30 MeV protons

type	part number	# irradiated	# broken
LDO regulator	MCP1727	9	0
	ADM7172	9	9
LVDS repeater clock driver	DS25BR100	8	0
	ADCLK846	8	0

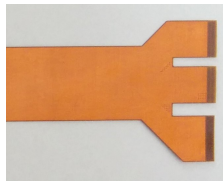
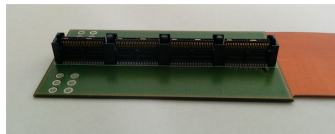
1.5 kGy, 2.9 GeV protons

type	part number	# irradiated	# broken
LDO regulator	MCP1727	10	0
	ADP1740	15	8
LVDS repeater clock driver	DS25BR440	4	2
	MAX9153	6	0
microcontroller	AT90CAN128	3	0

Rigid Flex Cable

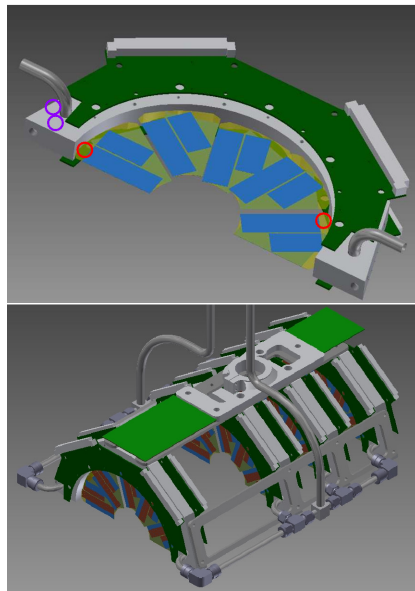


- Dimensions:
83 mm × 569 mm
- FFC connector outside of the box
- Three layers for flex area:
 - 40 differential pairs (signal, clock, ...)
 - High voltage
 - $\approx 500 \mu\text{m}$ thick
- Rigid area:
 - Connector for LV
 - High density, high power connector to half plane



Temperature sensors

- Temperature measurement inside of the detector necessary
 - 88 temperature sensors (PT100) foreseen:
 - 40 temperature sensors (on the diamonds) for monitoring
 - 48 temperature sensors (on the halfplanes and PCB) for overheating protection
- 352 wires
- Maybe NTC Thermistors on the HV-MAPS
 - Patch panel to combine single wires to a FPC

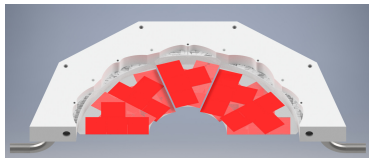


Low voltage

- HV-MAPS need 1.8 V (< 1.6 A)
- Voltage drop on flex cable up to 0.2 V
→ LDO regulator with sense pin necessary
- Use of MCP1727
 - Regulation: < 330 mV
 - $I_{Out} < 1.5$ A
 - Dimensions: 3 mm \times 3 mm
- Power supply: Wiener PL506 with MEH-02/07
 - Up to 115 A per channel
 - Master-Slave mode for paralleling of channels
 - Noise and ripple (datasheet): < 10 mV
- Use of a current bar in the detector to split the LV to the PCBs

High Voltage

- HV-MAPS need high voltage (> 60 V)
- Combine 5 sensors with one HV channel
- Power supply: ISEG EHS F205p-F
 - $U < 500$ V
 - 16 channels per module



- New design of flex cables in work
- Estimated voltage drop for the LV up to 0.2 V
→ Use of LDO regulator with sense pin
- Radiation test of electronic components are done
- Use of flex cables glued in feedthroughs

To Do

Test of the flex cables

Glueing test of the rigid flex cables

Design and test of the half plane pcb